TOSHIBA MT4S03A

**TENTATIVE** 

TOSHIBA TRANSISTOR SILICON NPN EPITAXIAL PLANAR TYPE

# **MT4S03A**

VHF~UHF BAND LOW NOISE AMPLIFIER APPLICATIONS

Low Noise: Figure: NF = 1.4 dB

High Gain : Gain = 9 dB (f = 2 GHz)

### MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Collector-Base Voltage	$v_{CBO}$	10	V
Collector-Emitter Voltage	$v_{CEO}$	5	V
Emitter-Base Voltage	$v_{\mathrm{EBO}}$	2	V
Base Current	$I_{\mathbf{C}}$	40	mA
Collector Current	$I_{\mathbf{B}}$	10	mA
Collector Power Dissipation	$P_{\mathbf{C}}$	150	mW
Junction Temperature	$T_{j}$	125	°C
Storage Temperature Range	$T_{ m stg}$	-55~125	°C

#### MARKING



# Unit in mm .90 0.85 0.55 + 0.25 1.50 – 0.15 8.0 $0.05 \pm 0.05$ 1, 3. EMITTER **BASE** 2. **COLLECTOR** SMQ **JEDEC EIAJ** TOSHIBA 2-3J1C

### MICROWAVE CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Transition Frequency	f <sub>T</sub> (1)	$V_{CE} = 1 \text{ V}, I_{C} = 5 \text{ mA}$	2	4.5	_	GHz
	f <sub>T</sub> (2)	$V_{CE} = 3 V, I_{C} = 10 mA$	7	10	_	
Insertion Gain	$ \mathbf{S}_{21e} ^2(1)$	$V_{ ext{CE}} = 1 \text{ V}, \text{ I}_{ ext{C}} = 5 \text{ mA},$ $f = 2 \text{ GHz}$	3.5	5.5	_	- dB
	$ S_{21e} ^2$ (2)	$V_{CE} = 3 \text{ V}, I_{C} = 20 \text{ mA}, $ f = 2 GHz	7	9	_	
Noise Figure	NF (1)	$V_{ ext{CE}} = 1 \text{ V}, \text{ I}_{ ext{C}} = 5 \text{ mA},$ $f = 2 \text{ GHz}$		1.7	3	dB
	NF (2)	$V_{ ext{CE}} = 3 \text{ V}, \text{ I}_{ ext{C}} = 7 \text{ mA},$ $f = 2 \text{ GHz}$	_	1.4	2.2	uD

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## ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Collector Cut-off Current	ICBO	$V_{CB} = 5 V, I_{E} = 0$	_	_	0.1	$\mu$ A
Emitter Cut-off Current	$I_{ m EBO}$	$V_{EB} = 1 V, I_{C} = 0$	_	_	1	$\mu$ A
DC Current Gain	$_{ m h_{FE}}$	$V_{CE} = 1 V$ , $I_{C} = 5 mA$	80	_	160	_
Reverse Transfer	C	$V_{CB} = 1 V, I_{E} = 0, f = 1 MHz$		0.7	1.05	рF
Capacitance	$\mathrm{C_{re}}$	(Note)	_	0.7	1.05	pr

(Note) :  $C_{re}$  is measured by 3 terminal method with capacitance bridge.

### CAUTION

This device electrostatic sensitivity. Please handle with caution.